COURSE DESCRIPTION CARD - SYLLABUS

Course name

SCANNING TUNNELING MICROSCOPY AND SPECTROSCOPY

Course

Proposed by Discipline	Year/Semester
Materials Engineering	II/3
Type of studies	Course offered in
Doctoral School	English
Form of study	Requirements
full-time	elective

Number of hours

Lecture	Tutorials	Projects/seminars
4		

Number of credit points

1

Lecturers

Responsible for the course/lecturer:

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Poznan University of Technology

ul. Piotrowo 3, 60-965 Poznan, Poland

Responsible for the course/lecturer:

Prerequisites

Knowledge: basic knowledge of the core course of physics and chemistry.

Skills: knowledge and ability to analyze experimental data.

Social competencies: understanding of the need to extend the level of competence; responsibility for the own work.

Course objective

1. Familiarize PhD students with the techniques of scanning tunneling microscopy (STM) and scanning tunneling spectroscopy (STS), commonly used in characterization of surfaces and nanostructures.

2. Developing PhD P8S_WG students' competencies to formulate and solve problems in physics and materials engineering at the nanometer scale.

Course-related learning outcomes

Knowledge

A PhD student who graduated from doctoral school knows and understands:

1) basic methods and techniques of scanning tunneling microscopy and spectroscopy, can describe the type of information they provide such as atomic structure of surfaces and nanostructures, their local density of electronic states (LDOS), magnetic properties at the nano- and subnano-meter scale, [P8S_WG/SzD_W01], [P8S_WG/SzD_W02]

2) the tunnel effect, its application in micro- and nano-scopy, as well in tunnel spectroscopy, can understand physical interpretation of the STM images and the current imaging tunneling spectroscopy spectra. [P8S_WG/SzD_W03]

Skills

A PhD student who graduated from doctoral school can:

1) analyze atomic structure of surfaces and nanostructures and correlate STM images with the local (at the atomic scale) electronic structure., [P8S_UW/SzD_U01]

Social competences

A PhD student who graduated from doctoral school is ready to:

1) acquire critically knowledge from a variety of sources, including Internet resources, [P8S_KK/SzD_K01]

2) precisely formulate problems and propose ways to resolve them, also in collaboration with team members. [P8S_KK/SzD_K03]

Methods for verifying learning outcomes and assessment criteria

Learning outcomes presented above are verified as follows:

PQF code	Methods for verification of learning outcomes	Assessment criteria
W01, W02, W03	Written exam - mark weight(significance): 0.6	sufficient – 50.1%-70.0%, good – 70.1%-90.0%, very good – > 90.1%
U01	Written exam - mark weight(significance): 0.3	sufficient – 50.1%-70.0%, good – 70.1%-90.0%, very good – > 90.1%
K01, K03	Written exam (evaluation of the litearature sources indicated by PhD student) - mark weight (significance): 0.1	sufficient – 50.1%-70.0%, good – 70.1%-90.0%, very good – > 90.1%

Programme content

1. General classification of the methods for imaging and characterization of materials (microscopic methods, spectroscopic methods).

2. Construction and operation of the scanning tunneling microscope (STM), basic operating modes and techniques of surface imaging (detection system, piezoelectric scanner and its calibration, feedback loop, constant current and constant height modes).

3. Image analysis and physical interpretation of the STM images; common causes of artifacts (revealing and analysis of the atomic structure of non-reconstructed and reconstructed surfaces, non-linearity of the scanner, mapping of the tip, incorrect feedback loop settings, incorrect image processing, thermal drift).

4. Basic operating modes and techniques of scanning tunneling spectroscopy (local I-V and dI/dV (dynamic conductance) curves measurements, current imaging tunneling spectroscopy methods (CITS), spin-polarized tunneling spectroscopy (SP-STS)).

5. Analysis of the scanning tunneling spectra and correlation with STM images (correlation between the STM topography images and CITS maps, analysis of the individual I-V and dI/dV(V) curves and CITS maps).

6. Comparison of scanning tunneling microscopy and spectroscopy with other methods of imaging and characterization of materials (scanning/transmission electron microscopy (S/TEM); LEED/Auger Spectroscopy, optical spectroscopies, spin-sensitive microscopy and spectroscopy).

Teaching methods

Lecture: multimedia presentation including illustrations and examples.

Bibliography

Basic

1. Roland Wiesendanger, Scanning Probe Microscopy and Spectroscopy: Methods and Applications, Cambridge University Press (2010).

2. R. Howland, L. Benatar, A practical guide to scanning probe microscopy, Park Scientific Instruments 2002.

Additional

1. R. J. Hamers and D. F. Padowitz, “Methods of Tunneling Spectroscopy with the STM,” from Scanning Probe Microscopy and Spectroscopy: Theory, Techniques, and Applications, 2nd ed., Ed. by D. A. Bonnell, New York: Wiley-VCH, Inc., 2001.

2. E. Meyer, H.J. Hug,R. Bennewitz, Scanning Probe Microscopy – The Lab on a Tip, Springer-Verlag, Berlin, 2003.

3. Nanoscience: Nanotechnologies and Nanophysics, C. Dupas, Ph. Houdy, M. Lahmani (Eds), Springer-Verlag, Berlin 2007.

Breakdown of average student's workload

	Hours	ECTS
Total workload	16	1,0
Classes requiring direct contact with the teacher	8	0,5
Student's own work (literature studies, preparation for tutorials, project preparation) [1]	8	0,5

[1] delete or add other activities as appropriate